

2021 IEEE 22nd Latin American Test Symposium (LATS 2021)

**Virtual Conference
27 – 29 October 2021**



**IEEE Catalog Number: CFP21LAT-POD
ISBN: 978-1-6654-2058-7**

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IEEE Catalog Number:	CFP21LAT-POD
ISBN (Print-On-Demand):	978-1-6654-2058-7
ISBN (Online):	978-1-6654-2057-0
ISSN:	2373-0862

Additional Copies of This Publication Are Available From:

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TECHNICAL PROGRAM

Opening Session (Message from the Organizing Committee)

General Chairs:

Raoul Velazco – TIMA (France)

Yervant Zorian – Synopsys (USA)

Program Chairs:

Leticia Maria Bolzani Pöhls – RWTH Aachen University (Germany)

Fabian Luis Vargas – PUCRS (Brazil)

Invited Talk 1

Session Chairs: Yervant Zorian, Synopsys (USA) and Fabian Luis Vargas, PUCRS (Brazil)

Hardware Security and Machine Learning: Hero or Hoax?...N/A

Prof. Giorgio di Natale, Université Grenoble Alpes (France)

Session 1: Diagnosis and On-Line Monitoring of Analog Circuits

Session Chair: Tiago Balen, UFRGS (Brazil)

Improved Fault Diagnosis of Analog Circuits using Light Emission Measures...1

Tommaso Melis, Emmanuel Simeu, Etienne Auvray and Luc Saury

Exploring On-Line RF Performance Monitoring based on the Indirect Test Strategy...7

Hassan El Badawi, Florence Azais, Serge Bernard, Mariane Comte, Vincent Kerzerho and François Lefevre

Session 2: Test and Reliability of Memories

Session Chair: Victor Champac, INAOE (Mexico)

Comparing different solutions for testing resistive defects in low power SRAMs...13

Nunzio Mirabella, Michelangelo Grosso, Giovanna Franchino, Salvatore Rinaudo, Ioannis Deretzis, Antonino La Magna and Matteo Sonza Reorda

Impact of DVS on power consumption and SEE sensitivity of COTS volatile SRAMs...19

Mohammadreza Rezaei, Francisco J Franco, Juan Carlos Fabero, Hortensia Mecha, Helmut Puchner and Juan Antonio Clemente



Embedded Tutorial 1

Session Chair: *Fabian Luis Vargas, PUCRS (Brazil)*

A Tutorial on Design Obfuscation: from Transistors to Systems...25
Prof. Samuel Pagliarini, Tallinn University of Technology (Estonia)

Visionary Talk

Session Chair: *Fabian Luis Vargas, PUCRS (Brazil)*

Fault Criticality Assessment in AI Accelerators: A Journey Through Systolic Arrays, ReRAM Crossbars, and Silicon Photonics...N/A
Prof. Krishnendu Chakrabarty, Duke University (USA)

Session 3: Radiation and Soft Errors in Memories and Logic Circuits

Session Chair: *Raoul Velazco, TIMA Lab (France)*

Thermal-Neutron Induced SEUs on a 28-nm SRAM-based FPGA under Different Incident Angles...28
Juan Carlos Fabero, Golnaz Korkian, Francisco J Franco, Hortensia Mecha, Manon Letiche and Juan Antonio Clemente

Total Ionizing Dose Effects on Floating Gate Structures: Preliminary Results...34
Sebastián Carbonetto, Luciano Genovese, Lucas Sambuco Salomone, Mariano Garcia Inza, Eduardo Gabriel Redin and Adrian Faigon

A COTS GaN Transistor is More Tolerant to Radiation in its ON State...N/A
Alexis Cristiano Vilas Bôas, Marco Melo, Renato Giacomini, Roberto Baginski Batista Santos, Nilberto Heder Medina, Luis Seixas, Saulo Finco, Rogelio Palomo and Marcilei Aparecida Guazzelli.

Exploring Gate Mapping and Transistor Sizing to Improve Radiation Robustness: A C17 Benchmark Case-Study...40
Bernardo Borges Sandoval, Leonardo H. Brendler, Alexandra Lackmann Zimpeck, Fernanda Kastensmidt, Ricardo Reis and Cristina Meinhardt

Invited Talk 2

Session Chair: *Raoul Velazco, TIMA Lab (France)*

Analyzing Data Extracted from Radiation Tests in Advanced SRAMs...N/A
Prof. Juan Antonio Clemente Barreira, UCM (Spain)



Embedded Tutorial 2

Session Chair: *Michelangelo Grosso, Politecnico di Torino (Italy)*

Approximate Computing for Safety-Critical Applications...46

Prof. Alberto Bosio, University Lyon (France); Gennaro Rodrigues, UFRGS (Brazil) and Fernanda Kastensmidt, UFRGS (Brazil)

Poster Session:

Session Chair: *Thiago Copetti, RWTH Aachen University (Germany)*

Towards SAT-Based SBST Generation for RISC-V Cores...49

Tobias Faller, Philipp Scholl, Tobias Paxian and Bernd Becker

SET Mitigation Techniques on Mirror Full Adder at 7nm FinFET Technology...51

Rafael Neves de Mello Oliveira, Fábio G. R. G. da Silva, Ricardo Reis and Cristina Meinhardt

TLP Generator Setup for Reliable Switching Characterization of Commercial GaN HEMTs...53

Carlos Bernal, Manuel Jimenez and Fabio Andrade

NETFI-2: A SEU and SET Fault-Emulation Methodology for HDL-Based Designs...N/A

Miguel Solinas, Dardo Vinas, Alexander Coelho, Juan Fraire, Juan Clemente and Pablo Ferreyra

EC Scalar Multiplication: Successful Simple Address-Bit SCA Attack against Atomic Patterns...56

Ievgen Kabin, Zoya Dyka, Dan Klann and Peter Langendoerfer

Invited Talk 3

Session Chair: *Maksim Jenihhin, Tallinn University of Technology (Estonia)*

New Defects in FinFET Technology, their Detection and Reliability Risk...N/A

Prof. Victor Champac, INAOE (Mexico)



Session 4: Understanding Variability and Reliability Impacts on Resistive RAMs

Session Chair: Jarbas Silveira, UFC (Brazil)

Evaluating the Impact of Process Variation on RRAMs...58

Eduardo Brum, Moritz Fieback, Thiago Santos Copetti, Jiayi He, Said Hamdioui, Fabian Vargas and Leticia Bolzani Poehls

Investigation of Single Event Effects in a Resistive RAM Memory Array by SPICE Level Simulation...64

Karine Coulié, Hassen Aziza and Wenceslas Rahajandraibe

Design Considerations Towards Zero-Variability Resistive RAMs in HRS State...70

Aziza Hassan, Karine Coulié and Wenceslas Rahajandraibe

Session 5: Fault Tolerant Systems

Session Chair: Felipe Restrepo Calle, Universidad Nacional de Colombia (Colombia)

Fault-Tolerant Quasi Delay Insensitive Combinational Circuits in Commercial FPGA Devices...75

Orlando Verducci, Duarte Oliveira and Robson Moreno

Reliability Evaluation of Voters for Fault Tolerant Approximate Systems...81

Tiago Balen, Carlos González, Ingrid Oliveira, Rafael Schwitz, Nemitala Added, Eduardo Macchione, Vitor Aguiar, Marcilei Guazzelli, Nilberto Medina and Paulo Butzen

Invited Talk 4

Session Chair: Fabian Luis Vargas, PUCRS (Brazil)

Trustworthy Autonomous Systems: Software-Hardware Error Resilience Using Hierarchical Algorithmic Checks...N/A

Prof. Abhijit Chatterjee, Georgia Institute of Technology (USA)

Industry Talk 1

Session Chair: Ievgen Kabin, IHP GmbH (Germany)

How to Feed a Growing Population while Conserving the Planet's Resources –IoT to the Rescue...N/A

Dr. Victor Grimblatt, Synopsys (Chile)



Industry Talk 2

Session Chair: Hans-Joachim Wunderlich, University of Stuttgart (Germany)

Soft Error becomes a Hard Problem for the Future Electronic Devices...N/A

Dr. Sung S. Chung, CTO, QRT Inc. Korea (Korea)

Session 6: Defect Modeling and Fault Injection Strategies

Session Chair: Julio Perez Acle, Universidad de la Republica de Uruguay (Uruguay)

Invited paper: Pros and Cons of Fault Injection Approaches for the Reliability Assessment of Deep Neural Networks...87

Annachiara Ruospo, Lucas Matana Luza, Alberto Bosio, Marcello Traiola, Luigi Dilillo and Ernesto Sanchez

Reliability Evaluation of RISC-V and ARM Microprocessors Through a New Fault Injection Tool...92

Alexander Aponte-Moreno, Felipe Restrepo-Calle and Cesar Pedraza Bonilla

Testing Embedded Software Through Fault Injection: Case Study on Smart Lock...98

Jakub Lojda, Richard Panek, Jakub Podivinsky, Ondrej Cekan, Martin Krcma and Zdenek Kotasek

Resistive Open Defect Classification of Embedded Cells under Variations...104

Zahra Paria Najafi Haghi and Hans-Joachim Wunderlich

Session 7: Designing Aerospace Applications

Session Chair: Emmanuel Simeu, Université Grenoble Alpes (France)

Evaluation of Attitude Estimation Algorithm under Soft Error Effects...110

João P. Brum, Tarso Sartori, Jiaru Lin, Matheus Trindade, Hassen Fourati, Raoul Velazco and Rodrigo Possamai Bastos

Nanosatellite On-Board Computer including a Many-Core Processor...115

Fabrice Pancher, Vanessa Vargas, Pablo Ramos, Rodrigo Possamai Bastos, David César Ardiles Saravia and Raoul Velazco